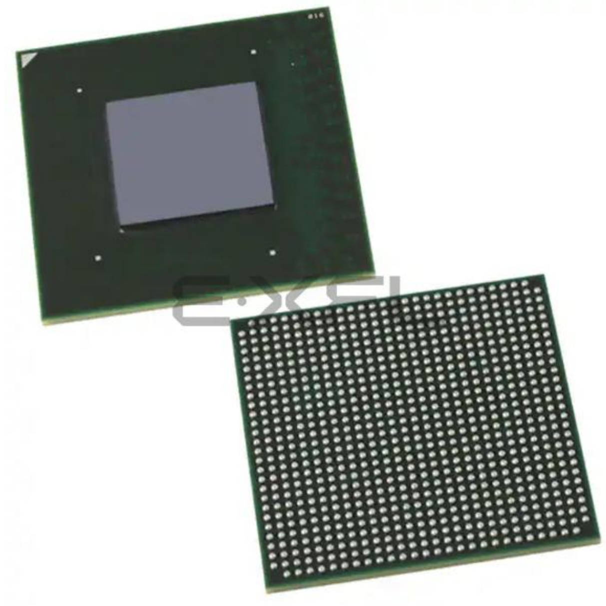
Intel - EP2AGX95EF29C6 Datasheet



Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	3747
Number of Logic Elements/Cells	89178
Total RAM Bits	6839296
Number of I/O	372
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	780-BBGA, FCBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2agx95ef29c6

The calibration accuracy for calibrated series and parallel OCTs are applicable at the moment of calibration. When process, voltage, and temperature (PVT) conditions change after calibration, the tolerance may change.

Table 1–13 lists the Arria II GZ OCT without calibration resistance tolerance to PVT changes.

Table 1–13. OCT Without Calibration Resistance Tolerance Specifications for Arria II GZ Devices

Symbol	Description	Conditions (V)	Resistance Tolerance		Unit
			C3,I3	C4,I4	
25-Ω R_S 3.0 and 2.5	25-Ω internal series OCT without calibration	V_{CCIO} = 3.0, 2.5	± 40	± 40	%
25-Ω R_S 1.8 and 1.5	25-Ω internal series OCT without calibration	V_{CCIO} = 1.8, 1.5	± 40	± 40	%
25-Ω R_S 1.2	25-Ω internal series OCT without calibration	V_{CCIO} = 1.2	± 50	± 50	%
50-Ω R_S 3.0 and 2.5	50-Ω internal series OCT without calibration	V_{CCIO} = 3.0, 2.5	± 40	± 40	%
50-Ω R_S 1.8 and 1.5	50-Ω internal series OCT without calibration	V_{CCIO} = 1.8, 1.5	± 40	± 40	%
50-Ω R_S 1.2	50-Ω internal series OCT without calibration	V_{CCIO} = 1.2	± 50	± 50	%
100-Ω R_D 2.5	100-Ω internal differential OCT	V_{CCIO} = 2.5	± 25	± 25	%

OCT calibration is automatically performed at power up for OCT-enabled I/Os. When voltage and temperature conditions change after calibration, the resistance may change. Use Equation 1–1 and Table 1–14 to determine the OCT variation when voltage and temperature vary after power-up calibration for Arria II GX and GZ devices.

Equation 1–1. OCT Variation ***(Note 1)***

$$R_{OCT} = R_{SCAL}\left(1 + \langle\frac{dR}{dT} \times \Delta T\rangle \pm \langle\frac{dR}{dV} \times \Delta V\rangle\right)$$

Notes to Equation 1–1:

(1) R_{OCT} value calculated from Equation 1–1shows the range of OCT resistance with the variation of temperature and V_{CCIO}.

Use the following with Equation 1–1:

- R_{SCAL} is the OCT resistance value at power up.
- ΔT is the variation of temperature with respect to the temperature at power up.
- ΔV is the variation of voltage with respect to the V_{CCIO} at power up.
- dR/dT is the percentage change of R_{SCAL} with temperature.
- dR/dV is the percentage change of R_{SCAL} with voltage.

Table 1–14 lists the OCT variation with temperature and voltage after power-up calibration for Arria II GX devices.

Table 1–14. OCT Variation after Power-up Calibration for Arria II GX Devices

Nominal Voltage V_{CCIO} (V)	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	0.035
2.5	0.234	0.039
1.8	0.219	0.086
1.5	0.199	0.136
1.2	0.161	0.288

Table 1–15 lists the OCT variation with temperature and voltage after power-up calibration for Arria II GZ devices.

Table 1–15. OCT Variation after Power-Up Calibration for Arria II GZ Devices *(Note 1)*

Nominal Voltage, V_{CCIO} (V)	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.189	0.0297
2.5	0.208	0.0344
1.8	0.266	0.0499
1.5	0.273	0.0744
1.2	0.317	0.1241

Note to Table 1–15:

(1) Valid for V_{CCIO} range of ±5% and temperature range of 0° to 85°C.

Pin Capacitance

Table 1–16 lists the pin capacitance for Arria II GX devices.

Table 1–16. Pin Capacitance for Arria II GX Devices

Symbol	Description	Typical	Unit
C_{IO}	Input capacitance on I/O pins, dual-purpose pins (differential I/O, clock, R_{up}, R_{dn}), and dedicated clock input pins	7	pF

Table 1–17 lists the pin capacitance for Arria II GZ devices.

Table 1–17. Pin Capacitance for Arria II GZ Devices

Symbol	Description	Typical	Unit
C_{IOTB}	Input capacitance on the top and bottom I/O pins	4	pF
C_{IOLR}	Input capacitance on the left and right I/O pins	4	pF
C_{CLKTB}	Input capacitance on the top and bottom non-dedicated clock input pins	4	pF
C_{CLKLR}	Input capacitance on the left and right non-dedicated clock input pins	4	pF
C_{OUTFB}	Input capacitance on the dual-purpose clock output and feedback pins	5	pF
C_{CLK1}, C_{CLK3}, C_{CLK8}, and C_{CLK10}	Input capacitance for dedicated clock input pins	2	pF

Internal Weak Pull-Up and Weak Pull-Down Resistors

Table 1–18 lists the weak pull-up and pull-down resistor values for Arria II GX devices.

Table 1–18. Internal Weak Pull-up and Weak Pull-Down Resistors for Arria II GX Devices *(Note 1)*

Symbol	Description	Conditions	Min	Typ	Max	Unit
R_{PU}	Value of I/O pin pull-up resistor before and during configuration, as well as user mode if the programmable pull-up resistor option is enabled.	V_{CCIO} = 3.3 V ±5% *(2)*	7	25	41	kΩ
		V_{CCIO} = 3.0 V ±5% *(2)*	7	28	47	kΩ
		V_{CCIO} = 2.5 V ±5% *(2)*	8	35	61	kΩ
		V_{CCIO} = 1.8 V ±5% *(2)*	10	57	108	kΩ
		V_{CCIO} = 1.5 V ±5% *(2)*	13	82	163	kΩ
		V_{CCIO} = 1.2 V ±5% *(2)*	19	143	351	kΩ
R_{PD}	Value of TCK pin pull-down resistor	V_{CCIO} = 3.3 V ±5%	6	19	29	kΩ
		V_{CCIO} = 3.0 V ±5%	6	22	32	kΩ
		V_{CCIO} = 2.5 V ±5%	6	25	42	kΩ
		V_{CCIO} = 1.8 V ±5%	7	35	70	kΩ
		V_{CCIO} = 1.5 V ±5%	8	50	112	kΩ

Notes to Table 1–18:

(1) All I/O pins have an option to enable weak pull-up except configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG TCK.

(2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

Table 1–26 lists the single-ended SSTL and HSTL I/O standard signal specifications for Arria II GX devices.

Table 1–26. Single-Ended SSTL and HSTL I/O Standard Signal Specifications for Arria II GX Devices

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	–0.3	V_{REF} - 0.18	V_{REF} + 0.18	V_{CCIO} + 0.3	V_{REF} - 0.35	V_{REF} + 0.35	V_{TT} - 0.57	V_{TT} + 0.57	8.1	–8.1
SSTL-2 Class II	–0.3	V_{REF} - 0.18	V_{REF} + 0.18	V_{CCIO} + 0.3	V_{REF} - 0.35	V_{REF} + 0.35	V_{TT} - 0.76	V_{TT} + 0.76	16.4	–16.4
SSTL-18 Class I	–0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	V_{TT} - 0.475	V_{TT} + 0.475	6.7	–6.7
SSTL-18 Class II	–0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	0.28	V_{CCIO} - 0.28	13.4	–13.4
SSTL-15 Class I	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	8	–8
SSTL-15 Class II	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	16	–16
HSTL-18 Class I	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	–8
HSTL-18 Class II	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	–16
HSTL-15 Class I	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	–8
HSTL-15 Class II	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	–16
HSTL-12 Class I	–0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	8	–8
HSTL-12 Class II	–0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	14	–14

Table 1–27 lists the single-ended SSTL and HSTL I/O standard signal specifications for Arria II GZ devices.

Table 1–27. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Arria II GZ Devices (Part 1 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	-0.3	V_{REF} - 0.15	V_{REF} + 0.15	V_{CCIO} + 0.3	V_{REF} - 0.31	V_{REF} + 0.31	V_{TT} - 0.57	V_{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	-0.3	V_{REF} - 0.15	V_{REF} + 0.15	V_{CCIO} + 0.3	V_{REF} - 0.31	V_{REF} + 0.31	V_{TT} - 0.76	V_{TT} + 0.76	16.2	-16.2
SSTL-18 Class I	-0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	V_{TT} - 0.475	V_{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	-0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	0.28	V_{CCIO} - 0.28	13.4	-13.4
SSTL-15 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	8	-8

Table 1–27. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Arria II GZ Devices (Part 2 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-15 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	16	-16
HSTL-18 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	-8
HSTL-18 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	-16
HSTL-15 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	-8
HSTL-15 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	-16
HSTL-12 Class I	-0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25× V_{CCIO}	0.75× V_{CCIO}	8	-8
HSTL-12 Class II	-0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25× V_{CCIO}	0.75 × V_{CCIO}	16	-16

Table 1–28 lists the differential SSTL I/O standards for Arria II GX devices.

Table 1–28. Differential SSTL I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)		$V_{OX(AC)}$ (V)		
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V_{CCIO}	V_{CCIO}/2 - 0.2	—	V_{CCIO}/2 + 0.2	0.7	V_{CCIO}	V_{CCIO}/2 - 0.15	—	V_{CCIO}/2 + 0.15
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO}	V_{CCIO}/2 - 0.175	—	V_{CCIO}/2 + 0.175	0.5	V_{CCIO}	V_{CCIO}/2 - 0.125	—	V_{CCIO}/2 + 0.125
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	—	V_{CCIO}/2	—	0.35	—	—	V_{CCIO}/2	—

Table 1–29 lists the differential SSTL I/O standards for Arria II GZ devices

Table 1–29. Differential SSTL I/O Standards for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)		$V_{OX(AC)}$ (V)		
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.2	—	V_{CCIO}/2 + 0.2	0.62	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.15	—	V_{CCIO}/2 + 0.15
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.175	—	V_{CCIO}/2 + 0.175	0.5	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.125	—	V_{CCIO}/2 + 0.125
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	—	V_{CCIO}/2	—	0.35	—	—	V_{CCIO}/2	—

Table 1–30 lists the HSTL I/O standards for Arria II GX devices.

Table 1–30. Differential HSTL I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.85	—	0.95	0.88	—	0.95	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.71	—	0.79	0.71	—	0.79	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	—	—	0.5 × V_{CCIO}	—	0.48 × V_{CCIO}	0.5 × V_{CCIO}	0.52 × V_{CCIO}	0.3	—

Table 1–31 lists the HSTL I/O standards for Arria II GZ devices.

Table 1–31. Differential HSTL I/O Standards for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V_{CCIO} + 0.3	—	0.5 × V_{CCIO}	—	0.4 × V_{CCIO}	0.5 × V_{CCIO}	0.6 × V_{CCIO}	0.3	V_{CCIO} + 0.48

Table 1–32 lists the differential I/O standard specifications for Arria II GX devices.

Table 1–32. Differential I/O Standard Specifications for Arria II GX Devices *(Note 1)*

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)			V_{ICM} (V) *(2)*		V_{OD} (V) *(3)*			V_{OCM} (V)		
	Min	Typ	Max	Min	Cond.	Max	Min	Max	Min	Typ	Max	Min	Typ	Max
2.5 V LVDS	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.05	1.80	0.247	—	0.6	1.125	1.25	1.375
RSDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.25	—	0.6	1	1.2	1.4
LVPECL *(5)*	2.375	2.5	2.625	300	—	—	0.6	1.8	—	—	—	—	—	—
BLVDS *(6)*	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—

Notes to Table 1–32*:*

(1) The 1.5 V PCML transceiver I/O standard specifications are described in "Transceiver Performance Specifications" on page 1–21.

(2) V_{IN} range: 0 <= V_{IN} <= 1.85 V.

(3) R_L range: 90 <= RL <= 110 Ω.

(4) The RSDS and mini-LVDS I/O standards are only supported for differential outputs.

(5) The LVPECL input standard is supported at the dedicated clock input pins (GCLK) only.

(6) There are no fixed V_{ICM}, V_{OD}, and V_{OCM} specifications for BLVDS. These specifications depend on the system topology.

Table 1–35. Transceiver Specifications for Arria II GZ Devices (Part 3 of 5)

Symbol/ Description	Conditions	–C3 and –I3 *(1)*			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Receiver DC Coupling Support	—	For more information about receiver DC coupling support, refer to the “DC-Coupled Links” section in the *Transceiver Architecture for Arria II Devices* chapter.						
Differential on-chip termination resistors	85–Ω setting	85 ± 20%			85 ± 20%			Ω
	100–Ω setting	100 ± 20%			100 ± 20%			Ω
	120–Ω setting	120 ± 20%			120 ± 20%			Ω
	150-Ω setting	150 ± 20%			150 ± 20%			Ω
Differential and common mode return loss	PCIe (Gen 1 and Gen 2), XAUI, HiGig+, CEI SR/LR, SRIO SR/LR, CPRI LV/HV, OBSAI, SATA	Compliant						—
Programmable PPM detector *(9)*	—	± 62.5, 100, 125, 200, 250, 300, 500, 1,000						ppm
Run length	—	—	—	200	—	—	200	UI
Programmable equalization	—	—	—	16	—	—	16	dB
t_{LTR} *(10)*	—	—	—	75	—	—	75	µs
$t_{LTR\_LTD\_Manual}$ *(11)*	—	15	—	—	15	—	—	µs
t_{LTD_Manual} *(12)*	—	—	—	4000	—	—	4000	ns
t_{LTD_Auto} *(13)*	—	—	—	4000	—	—	4000	ns
Receiver CDR 3 dB Bandwidth in lock-to-data (LTD) mode	PCIe Gen1	2.0 - 3.5						MHz
	PCIe Gen2	40 - 65						MHz
	(OIF) CEI PHY at 6.375 Gbps	20 - 35						MHz
	XAUI	10 - 18						MHz
	SRIO 1.25 Gbps	10 - 18						MHz
	SRIO 2.5 Gbps	10 - 18						MHz
	SRIO 3.125 Gbps	6 - 10						MHz
	GIGE	6 - 10						MHz
	SONET OC12	3 - 6						MHz
	SONET OC48	14 - 19						MHz
Receiver buffer and CDR offset cancellation time (per channel)	—	—	—	17000	—	—	17000	`reconfig_clk` cycles
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	3	—	—	3	—	dB
	DC Gain Setting = 2	—	6	—	—	6	—	dB

Figure 1–3 shows the differential receiver input waveform.

Figure 1–3. Receiver Input Waveform

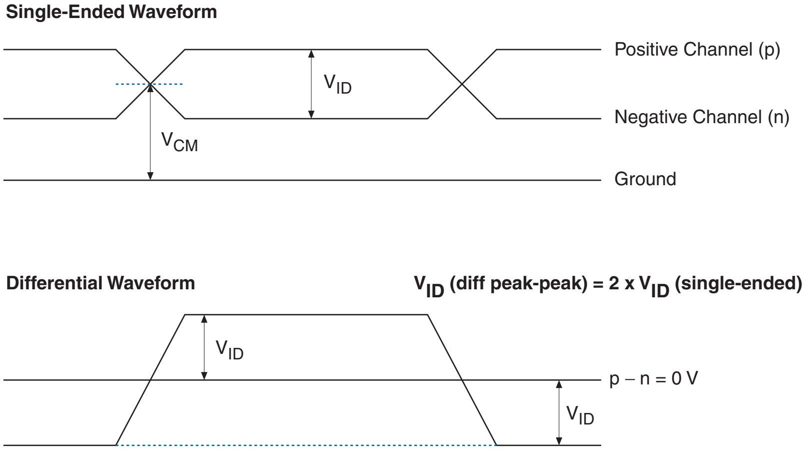


Figure 1–4 shows the transmitter output waveform.

Figure 1–4. Transmitter Output Waveform

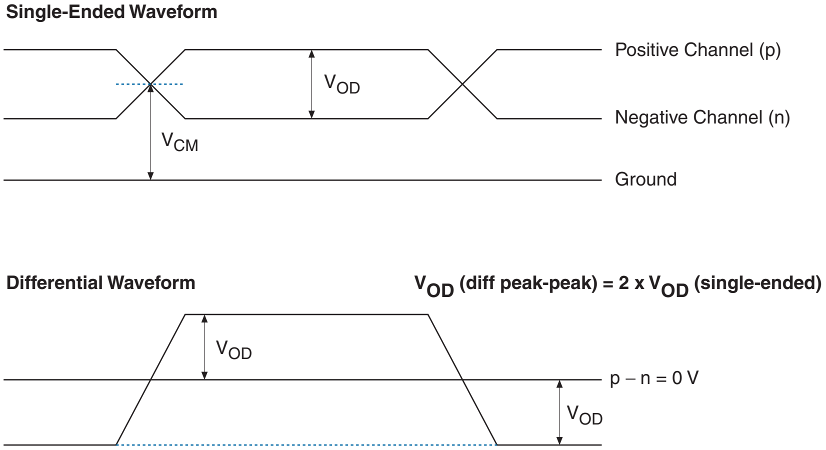


Table 1–36 lists the typical V_{OD} for TX term that equals 85 Ω for Arria II GZ devices.

Table 1–36. Typical V_{OD} Setting, TX Term = 85 Ω for Arria II GZ Devices

Symbol	V_{OD} Setting (mV)							
	0	1	2	3	4	5	6	7
V_{OD} differential peak-to-peak Typical (mV)	170 ± 20%	340 ± 20%	510 ± 20%	595 ± 20%	680 ± 20%	765 ± 20%	850 ± 20%	1020± 20%

Table 1–37 lists the typical V_{OD} for TX term that equals 100 Ω for Arria II GX and GZ devices.

Table 1–37. Typical V_{OD} Setting, TX Termination = 100 Ω for Arria II Devices

Quartus II Setting	V_{OD} Setting (mV)
1	400
2	600
3 (Arria II GZ)	700
4	800
5	900
6	1000
7	1200

Table 1–38 lists the typical transmitter pre-emphasis levels in dB for the first post tap under the following conditions: low-frequency data pattern (five 1s and five 0s) at 6.375 Gbps. The levels listed in Table 1–38 are a representation of possible pre-emphasis levels under these specified conditions only, the pre-emphasis levels may change with data pattern and data rate.

To predict the pre-emphasis level for your specific data rate and pattern, run simulations using the Arria II GX HSSI HSPICE models.

Table 1–38. Transmitter Pre-Emphasis Levels for Arria II GX Devices

Arria II GX (Quartus II Software) First Post Tap Setting	Arria II GX (Quartus II Software) VOD Setting						
	1	**2**	**4**	**5**	**6**	**7**	**Unit**
0 (off)	0	0	0	0	0	0	—
1	0.7	0	0	0	0	0	dB
2	2.7	1.2	0.3	0	0	0	dB
3	4.9	2.4	1.2	0.8	0.5	0.2	dB
4	7.5	3.8	2.1	1.6	1.2	0.6	dB
5	—	5.3	3.1	2.4	1.8	1.1	dB
6	—	7	4.3	3.3	2.7	1.7	dB

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices *(Note 1)* **(Part 2 of 10)**

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	**Typ**	**Max**	**Min**	**Typ**	**Max**	**Min**	**Typ**	**Max**	**Min**	**Typ**	**Max**	
Jitter tolerance at 2488.32 Mbps	Jitter frequency = 0.06 KHz Pattern = PRBS15	> 15			> 15			> 15			> 15			UI
	Jitter frequency = 100 KHZ Pattern = PRBS15	> 1.5			> 1.5			> 1.5			> 1.5			UI
	Jitter frequency = 1 MHz Pattern = PRBS15	> 0.15			> 0.15			> 0.15			> 0.15			UI
	Jitter frequency = 10 MHz Pattern = PRBS15	> 0.15			> 0.15			> 0.15			> 0.15			UI
XAUI Transmit Jitter Generation *(3)*														
Total jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.3	—	—	0.3	—	—	0.3	—	—	0.3	UI
Deterministic jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.17	—	—	0.17	—	—	0.17	—	—	0.17	UI
XAUI Receiver Jitter Tolerance *(3)*														
Total jitter	—	> 0.65			> 0.65			> 0.65			> 0.65			UI
Deterministic jitter	—	> 0.37			> 0.37			> 0.37			> 0.37			UI
Peak-to-peak jitter	Jitter frequency = 22.1 KHz	> 8.5			> 8.5			> 8.5			> 8.5			UI
Peak-to-peak jitter	Jitter frequency = 1.875 MHz	> 0.1			> 0.1			> 0.1			> 0.1			UI
Peak-to-peak jitter	Jitter frequency = 20 MHz	> 0.1			> 0.1			> 0.1			> 0.1			UI
PCIe Transmit Jitter Generation *(4)*														
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	—	—	0.25	—	—	0.25	—	—	0.25	—	—	0.25	UI

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices ***(Note 1)*** **(Part 3 of 10)**

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
PCIe Receiver Jitter Tolerance ***(4)***														
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	> 0.6			> 0.6			> 0.6			> 0.6			UI
PCIe (Gen 1) Electrical Idle Detect Threshold ***(9)***														
VRX-IDLE-DETDIFF (p-p)	Compliance pattern	65	—	175	65	—	175	65	—	175	65	—	175	mV
Serial RapidIO® (SRIO) Transmit Jitter Generation ***(5)***														
Deterministic jitter (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	—	—	0.17	—	—	0.17	—	—	0.17	—	—	0.17	UI
Total jitter (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	—	—	0.35	—	—	0.35	—	—	0.35	—	—	0.35	UI
SRIO Receiver Jitter Tolerance ***(5)***														
Deterministic jitter tolerance (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.37			> 0.37			> 0.37			> 0.37			UI
Combined deterministic and random jitter tolerance (peak-to-peak)	Data Rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.55			> 0.55			> 0.55			> 0.55			UI
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 22.1 KHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 8.5			> 8.5			> 8.5			> 8.5			UI
	Jitter frequency = 1.875 MHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI
	Jitter frequency = 20 MHz Data rate = 1.25, 2.5, 3.125 Gbps Pattern = CJPAT	> 0.1			> 0.1			> 0.1			> 0.1			UI
GIGE Transmit Jitter Generation ***(6)***														
Deterministic jitter (peak-to-peak)	Pattern = CRPAT	—	—	0.14	—	—	0.14	—	—	0.14	—	—	0.14	UI

Core Performance Specifications for the Arria II Device Family

This section describes the clock tree, phase-locked loop (PLL), digital signal processing (DSP), embedded memory, configuration, and JTAG specifications for Arria II GX and GZ devices.

Clock Tree Specifications

Table 1–42 lists the clock tree specifications for Arria II GX devices.

Table 1–42. Clock Tree Performance for Arria II GX Devices

Clock Network	Performance			Unit
	I3, C4	C5,I5	C6	
GCLK and RCLK	500	500	400	MHz
PCLK	420	350	280	MHz

Table 1–43 lists the clock tree specifications for Arria II GZ devices.

Table 1–43. Clock Tree Performance for Arria II GZ Devices

Clock Network	Performance		Unit
	–C3 and –I3	–C4 and –I4	
GCLK and RCLK	700	500	MHz
PCLK	500	450	MHz

PLL Specifications

Table 1–44 lists the PLL specifications for Arria II GX devices.

Table 1–44. PLL Specifications for Arria II GX Devices (Part 1 of 3)

Symbol	Description	Min	Typ	Max	Unit
f_{IN}	Input clock frequency (from clock input pins residing in right/top/bottom banks) (–4 Speed Grade)	5	—	670 *(1)*	MHz
	Input clock frequency (from clock input pins residing in right/top/bottom banks) (–5 Speed Grade)	5	—	622 *(1)*	MHz
	Input clock frequency (from clock input pins residing in right/top/bottom banks) (–6 Speed Grade)	5	—	500 *(1)*	MHz
f_{INPFD}	Input frequency to the PFD	5	—	325	MHz
f_{VCO}	PLL VCO operating Range *(2)*	600	—	1,400	MHz
f_{INDUTY}	Input clock duty cycle	40	—	60	%
$f_{EINDUTY}$	External feedback clock input duty cycle	40	—	60	%
t_{INCCJ} *(3)*, *(4)*	Input clock cycle-to-cycle jitter (Frequency ≥ 100 MHz)	—	—	0.15	UI (p–p)
	Input clock cycle-to-cycle jitter (Frequency ≤ 100 MHz)	—	—	±750	ps (p–p)

Table 1–45. PLL Specifications for Arria II GZ Devices (Part 2 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	—	—	1	ms
f_{CLBW}	PLL closed-loop low bandwidth	—	0.3	—	MHz
	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth *(7)*	—	4	—	MHz
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps
t_{ARESET}	Minimum pulse width on the `areset` signal	10	—	—	ns
t_{INCCJ} *(3)*, *(4)*	Input clock cycle to cycle jitter ($F_{REF} \geq 100$ MHz)	—	—	0.15	UI (p-p)
	Input clock cycle to cycle jitter ($F_{REF} < 100$ MHz)	—	—	±750	ps (p-p)
t_{OUTPJ_DC} *(5)*	Period Jitter for dedicated clock output ($F_{OUT} \geq 100$ MHz)	—	—	175	ps (p-p)
	Period Jitter for dedicated clock output ($F_{OUT} < 100$ MHz)	—	—	17.5	mUI (p-p)
t_{OUTCCJ_DC} *(5)*	Cycle to Cycle Jitter for dedicated clock output ($F_{OUT} \geq 100$ MHz)	—	—	175	ps (p-p)
	Cycle to Cycle Jitter for dedicated clock output ($F_{OUT} < 100$ MHz)	—	—	17.5	mUI (p-p)
t_{OUTPJ_IO} *(5)*, *(8)*	Period Jitter for clock output on regular I/O ($F_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Period Jitter for clock output on regular I/O ($F_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
t_{OUTCCJ_IO} *(5)*, *(8)*	Cycle to Cycle Jitter for clock output on regular I/O ($F_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Cycle to Cycle Jitter for clock output on regular I/O ($F_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{CASC\_OUTPJ\_DC}$ *(5)*, *(6)*	Period Jitter for dedicated clock output in cascaded PLLs ($F_{OUT} \geq 100$MHz)	—	—	250	ps (p-p)
	Period Jitter for dedicated clock output in cascaded PLLs ($F_{OUT} < 100$MHz)	—	—	25	mUI (p-p)
f_{DRIFT}	Frequency drift after PFDENA is disabled for duration of 100 us	—	—	±10	%

Notes to Table 1–45:

(1) This specification is limited in the Quartus II software by the I/O maximum frequency. The maximum I/O frequency is different for each I/O standard.

(2) This specification is limited by the lower of the two: I/O F_{MAX} or F_{OUT} of the PLL.

(3) A high input jitter directly affects the PLL output jitter. To have low PLL output clock jitter, you must provide a clean clock source that is less than 120 ps.

(4) F_{REF} is fIN/N when N = 1.

(5) Peak-to-peak jitter with a probability level of 10^{-12} (14 sigma, 99.99999999974404% confidence level). The output jitter specification applies to the intrinsic jitter of the PLL, when an input jitter of 30 ps is applied. The external memory interface clock output jitter specifications use a different measurement method and are available in Table 1–64 on page 1–71.

(6) The cascaded PLL specification is only applicable with the following condition:
a. Upstream PLL: 0.59 Mhz ≤ Upstream PLL BW < 1 MHz
b. Downstream PLL: Downstream PLL BW > 2 MHz

(7) High bandwidth PLL settings are not supported in external feedback mode.

(8) External memory interface clock output jitter specifications use a different measurement method, which is available in Table 1–63 on page 1–71.

DSP Block Specifications

Table 1–46 lists the DSP block performance specifications for Arria II GX devices.

Table 1–46. DSP Block Performance Specifications for Arria II GX Devices *(Note 1)*

Mode	Resources Used	Performance				Unit
	Number of Multipliers	C4	I3	C5,I5	C6	
9 × 9-bit multiplier	1	380	310	300	250	MHz
12 × 12-bit multiplier	1	380	310	300	250	MHz
18 × 18-bit multiplier	1	380	310	300	250	MHz
36 × 36-bit multiplier	1	350	270	270	220	MHz
18 × 36-bit high-precision multiplier adder mode	1	350	270	270	220	MHz
18 × 18-bit multiply accumulator	4	380	310	300	250	MHz
18 × 18-bit multiply adder	4	380	310	300	250	MHz
18 × 18-bit multiply adder-signed full precision	2	380	310	300	250	MHz
18 × 18-bit multiply adder with loopback *(2)*	2	275	220	220	180	MHz
36-bit shift (32-bit data)	1	350	270	270	220	MHz
Double mode	1	350	270	270	220	MHz

Notes to Table 1–46:

(1) Maximum is for a fully-pipelined block with **Round** and **Saturation** disabled.

(2) Maximum is for loopback input registers disabled, **Round** and **Saturation** disabled, pipeline and output registers enabled.

Table 1–47 lists the DSP block performance specifications for Arria II GZ devices.

Table 1–47. DSP Block Performance Specifications for Arria II GZ Devices *(Note 1)* (Part 1 of 2)

Mode	Resources Used	Performance		Unit
	Number of Multipliers	–3	–4	
9 × 9-bit multiplier	1	460	400	MHz
12 × 12-bit multiplier	1	500	440	MHz
18 × 18-bit multiplier	1	550	480	MHz
36 × 36-bit multiplier	1	440	380	MHz
18 × 18-bit multiply accumulator	4	440	380	MHz
18 × 18-bit multiply adder	4	470	410	MHz
18 × 18-bit multiply adder-signed full precision	2	450	390	MHz
18 × 18-bit multiply adder with loopback *(2)*	2	350	310	MHz
36-bit shift (32-bit data)	1	440	380	MHz

Table 1–47. DSP Block Performance Specifications for Arria II GZ Devices *(Note 1)* (Part 2 of 2)

Mode	Resources Used	Performance		Unit
	Number of Multipliers	–3	–4	
Double mode	1	440	380	MHz

Notes to Table 1–47:

(1) Maximum is for fully pipelined block with **Round** and **Saturation** disabled.

(2) Maximum for loopback input registers disabled, **Round** and **Saturation** disabled, and pipeline and output registers enabled.

Embedded Memory Block Specifications

Table 1–48 lists the embedded memory block specifications for Arria II GX devices.

Table 1–48. Embedded Memory Block Performance Specifications for Arria II GX Devices

Memory	Mode	Resources Used		Performance				Unit
		ALUTs	Embedded Memory	I3	C4	C5,I5	C6	
Memory Logic Array Block (MLAB)	Single port 64 × 10	0	1	450	500	450	378	MHz
	Simple dual-port 32 × 20 single clock	0	1	270	500	450	378	MHz
	Simple dual-port 64 × 10 single clock	0	1	428	500	450	378	MHz
M9K Block	Single-port 256 × 36	0	1	360	400	360	310	MHz
	Single-port 256 × 36, with the **read-during-write** option set to **Old Data**	0	1	250	280	250	210	MHz
	Simple dual-port 256 × 36 single CLK	0	1	360	400	360	310	MHz
	Single-port 256 × 36 single CLK, with the **read-during-write** option set to **Old Data**	0	1	250	280	250	210	MHz
	True dual port 512 × 18 single CLK	0	1	360	400	360	310	MHz
	True dual-port 512 × 18 single CLK, with the **read-during-write** option set to **Old Data**	0	1	250	280	250	210	MHz
	Min Pulse Width (clock high time)	—	—	900	850	950	1130	ps
	Min Pulse Width (clock low time)	—	—	730	690	770	920	ps

Periphery Performance

This section describes periphery performance, including high-speed I/O, external memory interface, and IOE programmable delay.

I/O performance supports several system interfaces, for example the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/O using SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speed with typical DDR2 SDRAM memory interface setup. I/O using general purpose I/O (GPIO) standards such as 3.0, 2.5, 1.8, or 1.5 LVTTL/LVCMOS are capable of typical 200 MHz interfacing frequency with 10pF load.

☞ Actual achievable frequency depends on design- and system-specific factors. You should perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 1–53 lists the high-speed I/O timing for Arria II GX devices.

Table 1–53. High-Speed I/O Specifications for Arria II GX Devices (Part 1 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Clock										
f_{HSCLK_IN} (input clock frequency)–Row I/O	Clock boost factor, W = 1 to 40 *(1)*	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_IN} (input clock frequency)–Column I/O	Clock boost factor, W = 1 to 40 *(1)*	5	500	5	500	5	472.5	5	472.5	MHz
f_{HSCLK_OUT} (output clock frequency)–Row I/O	—	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_OUT} (output clock frequency)–Column I/O	—	5	500	5	500	5	472.5	5	472.5	MHz

Table 1–54. High-Speed I/O Specifications for Arria II GZ Devices *(Note 1), (2), (10)* **(Part 3 of 3)**

Symbol	Conditions	C3, I3			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	
t_{RISE} & t_{FALL}	True differential I/O standards	—	—	200	—	—	200	ps
	Emulated differential I/O standards with three external output resistor networks	—	—	250	—	—	300	ps
	Emulated differential I/O standards with one external output resistor	—	—	500	—	—	500	ps
TCCS	True LVDS	—	—	100	—	—	100	ps
	Emulated LVDS_E_3R	—	—	250	—	—	250	ps
Receiver								
True differential I/O standards - $f_{HSDRDPA}$ (data rate)	SERDES factor J = 3 to 10	150	—	1250	150	—	1250	Mbps
f_{HSDR} (data rate)	SERDES factor J = 3 to 10	*(4)*	—	*(6)*	*(4)*	—	*(6)*	Mbps
	SERDES factor J = 2, uses DDR registers	*(4)*	—	*(5)*	*(4)*	—	*(5)*	Mbps
	SERDES factor J = 1, uses an SDR register	*(4)*	—	*(5)*	*(4)*	—	*(5)*	Mbps
DPA run length	DPA mode	—	—	10000	—	—	10000	UI
Soft-CDR PPM tolerance	Soft-CDR mode	—	—	300	—	—	300	± PPM
Sampling Window (SW)	Non-DPA mode	—	—	300	—	—	300	ps

Notes to Table 1–54:

(1) When J = 3 to 10, use the SERDES block.

(2) When J = 1 or 2, bypass the SERDES block.

(3) Clock Boost Factor (W) is the ratio between input data rate to the input clock rate.

(4) The minimum specification depends on the clock source (for example, the PLL and clock pin) and the clock routing resource (global, regional, or local) that you use. The I/O differential buffer and input register do not have a minimum toggle rate.

(5) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine leftover timing margin.

(6) You can estimate the achievable maximum data rate for non-DPA mode by performing link timing closure analysis. You must consider the board skew margin, transmitter delay margin, and the receiver sampling margin to determine the maximum data rate supported.

(7) This is achieved by using the LVDS and DPA clock network.

(8) If the receiver with DPA enabled and transmitter are using shared PLLs, the minimum data rate is 150 Mbps.

(9) This only applies to DPA and soft-CDR modes.

(10) This only applies to LVDS source synchronous mode.

Table 1–55 lists DPA lock time specifications for Arria II GX and GZ devices.

Table 1–60 lists the DQS phase shift error for Arria II GX devices.

Table 1–60. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria II GX Devices *(Note 1)*

Number of DQS Delay Buffer	C4	I3, C5, I5	C6	Unit
1	26	30	36	ps
2	52	60	72	ps
3	78	90	108	ps
4	104	120	144	ps

Note to Table 1–60:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a C4 speed grade is ± 78 ps or ± 39 ps.

Table 1–61 lists the DQS phase shift error for Arria II GZ devices.

Table 1–61. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria II GZ Devices *(Note 1)*

Number of DQS Delay Buffer	–3	–4	Unit
1	28	30	ps
2	56	60	ps
3	84	90	ps
4	112	120	ps

Note to Table 1–61:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a 3 speed grade is ± 84 ps or ± 42 ps.

Table 1–62 lists the memory output clock jitter specifications for Arria II GX devices.

Table 1–62. Memory Output Clock Jitter Specification for Arria II GX Devices *(Note 1)*, *(2)*, *(3)*

Parameter	Clock Network	Symbol	–4		–5		–6		Unit
			Min	Max	Min	Max	Min	Max	
Clock period jitter	Global	$t_{JIT(per)}$	-100	100	-125	125	-125	125	ps
Cycle-to-cycle period jitter	Global	$t_{JIT(cc)}$	-200	200	-250	250	-250	250	ps
Duty cycle jitter	Global	$t_{JIT(duty)}$	-100	100	-125	125	-125	125	ps

Notes to Table 1–62:

(1) The memory output clock jitter measurements are for 200 consecutive clock cycles, as specified in the JEDEC DDR2/DDR3 SDRAM standard.

(2) The clock jitter specification applies to memory output clock pins generated using DDIO circuits clocked by a PLL output routed on a global clock network.

(3) The memory output clock jitter stated in Table 1–62 is applicable when an input jitter of 30 ps is applied.

Table 1–63 lists the memory output clock jitter specifications for Arria II GZ devices.

Table 1–63. Memory Output Clock Jitter Specification for Arria II GZ Devices *(Note 1)*, *(2)*, *(3)*

Parameter	Clock Network	Symbol	–3		–4		Unit
			Min	Max	Min	Max	
Clock period jitter	Regional	$t_{JIT(per)}$	-55	55	-55	55	ps
Cycle-to-cycle period jitter	Regional	$t_{JIT(cc)}$	-110	110	-110	110	ps
Duty cycle jitter	Regional	$t_{JIT(duty)}$	-82.5	82.5	-82.5	82.5	ps
Clock period jitter	Global	$t_{JIT(per)}$	-82.5	82.5	-82.5	82.5	ps
Cycle-to-cycle period jitter	Global	$t_{JIT(cc)}$	-165	165	-165	165	ps
Duty cycle jitter	Global	$t_{JIT(duty)}$	-90	90	-90	90	ps

Notes to Table 1–63:

(1) The memory output clock jitter measurements are for 200 consecutive clock cycles, as specified in the JEDEC DDR2/DDR3 SDRAM standard.

(2) The clock jitter specification applies to memory output clock pins generated using differential signal-splitter and DDIO circuits clocked by a PLL output routed on a regional or global clock network as specified. Altera recommends using regional clock networks whenever possible.

(3) The memory output clock jitter stated in Table 1–63 is applicable when an input jitter of 30 ps is applied.

Duty Cycle Distortion (DCD) Specifications

Table 1–64 lists the worst-case DCD specifications for Arria II GX devices.

Table 1–64. Duty Cycle Distortion on I/O Pins for Arria II GX Devices *(Note 1)*

Symbol	C4		I3, C5, I5		C6		Unit
	Min	Max	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	45	55	%

Note to Table 1–64:

(1) The DCD specification applies to clock outputs from the PLL, global clock tree, IOE driving dedicated, and general purpose I/O pins.

Table 1–65 lists the worst-case DCD specifications for Arria II GZ devices.

Table 1–65. Duty Cycle Distortion on I/O Pins for Arria II GZ Devices *(Note 1)*

Symbol	C3, I3		C4, I4		Unit
	Min	Max	Min	Max	
Output Duty Cycle	45	55	45	55	%

Note to Table 1–65:

(1) The DCD specification applies to clock outputs from the PLL, global clock tree, IOE driving dedicated, and general purpose I/O pins.

Table 1–69. Document Revision History (Part 2 of 2)

Date	Version	Changes
December 2010	4.0	■ Added Arria II GZ information. ■ Added Table 1–61 with Arria II GX information. ■ Updated Table 1–1, Table 1–2, Table 1–5, Table 1–6, Table 1–7, Table 1–11, Table 1–35, Table 1–37, Table 1–40, Table 1–42, Table 1–44, Table 1–45, Table 1–57, Table 1–61, and Table 1–63. ■ Updated Figure 1–5. ■ Updated for the Quartus II version 10.0 release. ■ Updated the first paragraph for searchability. ■ Minor text edits.
July 2010	3.0	■ Updated Table 1–1, Table 1–4, Table 1–16, Table 1–19, Table 1–21, Table 1–23, Table 1–25, Table 1–26, Table 1–30, and Table 1–35 ■ Added Table 1–27 and Table 1–29. ■ Added I3 speed grade information to Table 1–19, Table 1–21, Table 1–22, Table 1–24, Table 1–25, Table 1–30, Table 1–32, Table 1–33, Table 1–34, and Table 1–35. ■ Updated the “Operating Conditions” section. ■ Removed “Preliminary” from Table 1–19, Table 1–21, Table 1–22, Table 1–23, Table 1–24, Table 1–25, Table 1–26, Table 1–28, Table 1–30, Table 1–32, Table 1–33, Table 1–34, and Figure 1–4. ■ Minor text edits.
March 2010	2.3	Updated for the Quartus II version 9.1 SP2 release: ■ Updated Table 1–3, Table 1–7, Table 1–19, Table 1–21, Table 1–22, Table 1–24, Table 1–25 and Table 1–33. ■ Updated “Recommended Operating Conditions” section. ■ Minor text edits.
February 2010	2.2	Updated Table 1–19.
February 2010	2.1	Updated for Arria II GX v9.1 SP1 release: ■ Updated Table 1–19, Table 1–23, Table 1–28, Table 1–30, and Table 1–33. ■ Added Figure 1–5. ■ Minor text edits.
November 2009	2.0	Updated for Arria II GX v9.1 release: ■ Updated Table 1–1, Table 1–4, Table 1–13, Table 1–14, Table 1–19, Table 1–15, Table 1–22, Table 1–24, and Table 1–28. ■ Added Table 1–6 and Table 1–33. ■ Added “Bus Hold” on page 1–5. ■ Added “IOE Programmable Delay” section. ■ Minor text edit.
June 2009	1.2	■ Updated Table 1–1, Table 1–3, Table 1–7, Table 1–8, Table 1–18, Table 1–23, Table 1–25, Table 1–26, Table 1–29, Table 1–30, Table 1–31, Table 1–32, and Table 1–33. ■ Added Table 1–32. ■ Updated Equation 1–1.
March 2009	1.1	Added “I/O Timing” section.
February 2009	1.0	Initial release.